

# Single-Photon Detector & Metrology Efforts at NIST

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[photon.jqi.umd.edu/spw2009](http://photon.jqi.umd.edu/spw2009)



# Single-Photon Detector Efforts

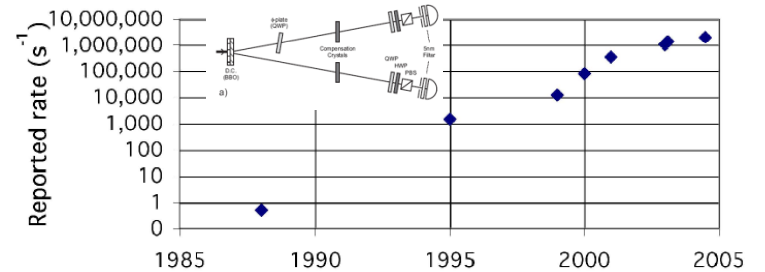
- Detectors
  - Deadtime reduction by
    - space multiplexing
    - avalanche photodiode- advanced electronics
    - smart processing
- Metrology
  - Correlated Photon Method
  - Transfer Standard Method
  - High-gain low-noise transfer standard to disseminate calibrations
  - Bridging the gap between cryogenic radiometry & photon counting
- Coincidence counting
  - Simple FPGA-based multi-coincidence analyzer

# Detectors: The problem

(good news & bad news)

- Single photon & entangled photon sources are getting brighter  
~5 MHz

History of Entangled Photon Pair Production



Kwiat, et al QCMC 2004

- Detector count rates are limited
  - absolute max rates ~5-15 MHz
  - practical max rates ~1 MHz
    - Deadtime ~50 ns(vis) 10  $\mu$ s(NIR)
    - Afterpulsing ~1 – 10<sup>-3</sup>

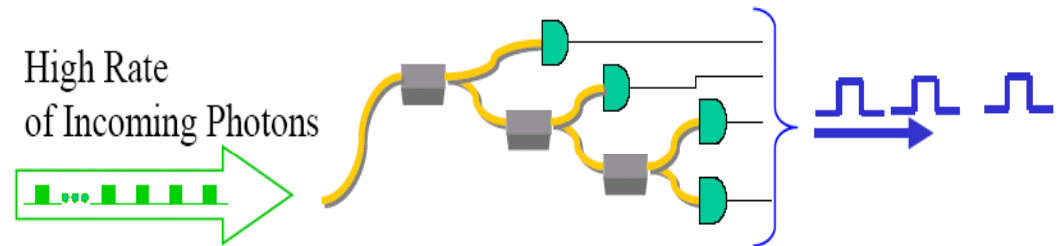
Overloading the system



# Ways to reduce effective deadtime:

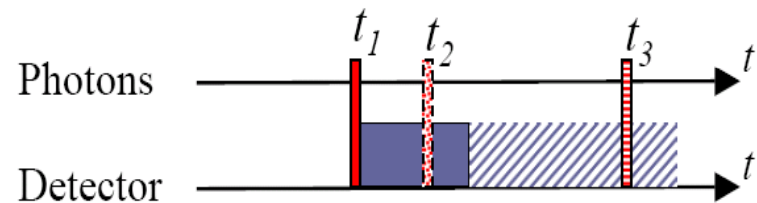
## Detector Tree:

a detection apparatus based on a set of detectors used in “tree” configuration



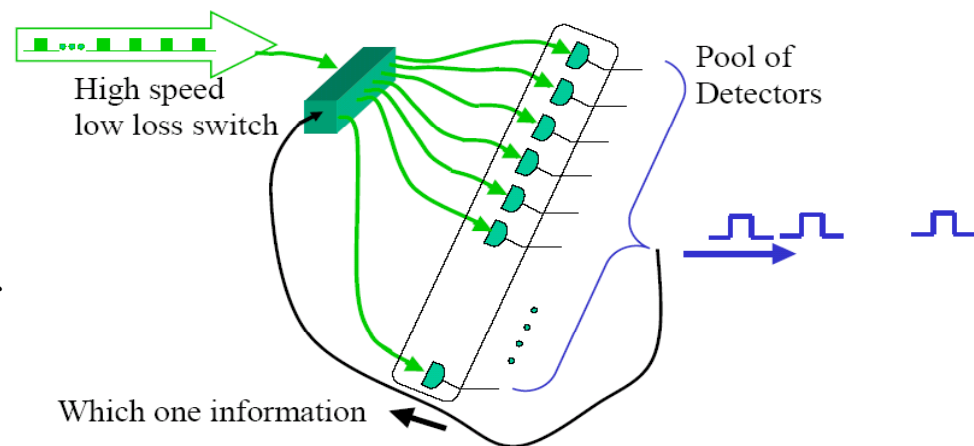
## Improved Single Detector with Reduced Deadtime:

technological efforts to reduce the deadtime of the single detector

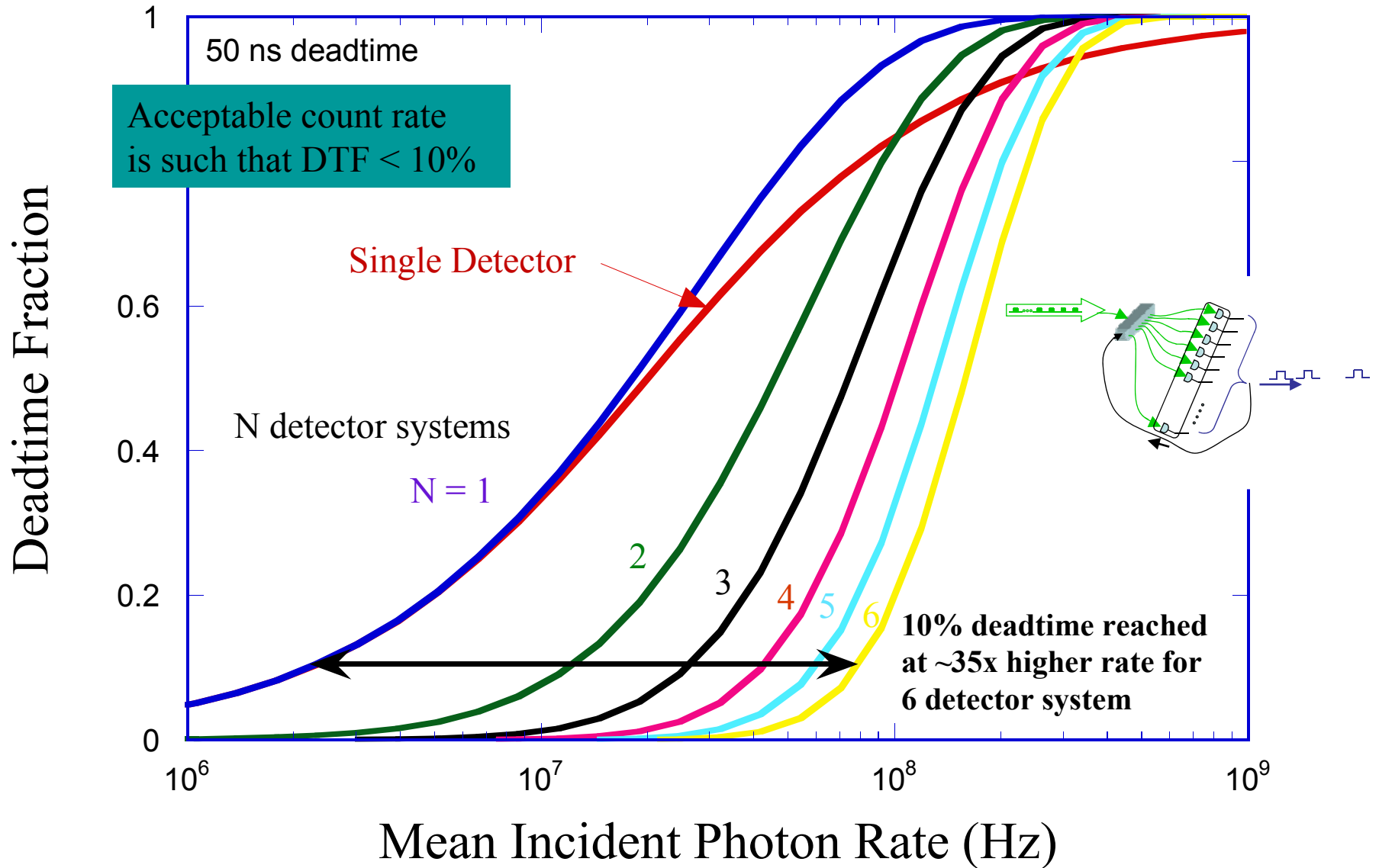


## Multiplexed Detector Array:

a detection apparatus based on an active optical switch and an array of detectors



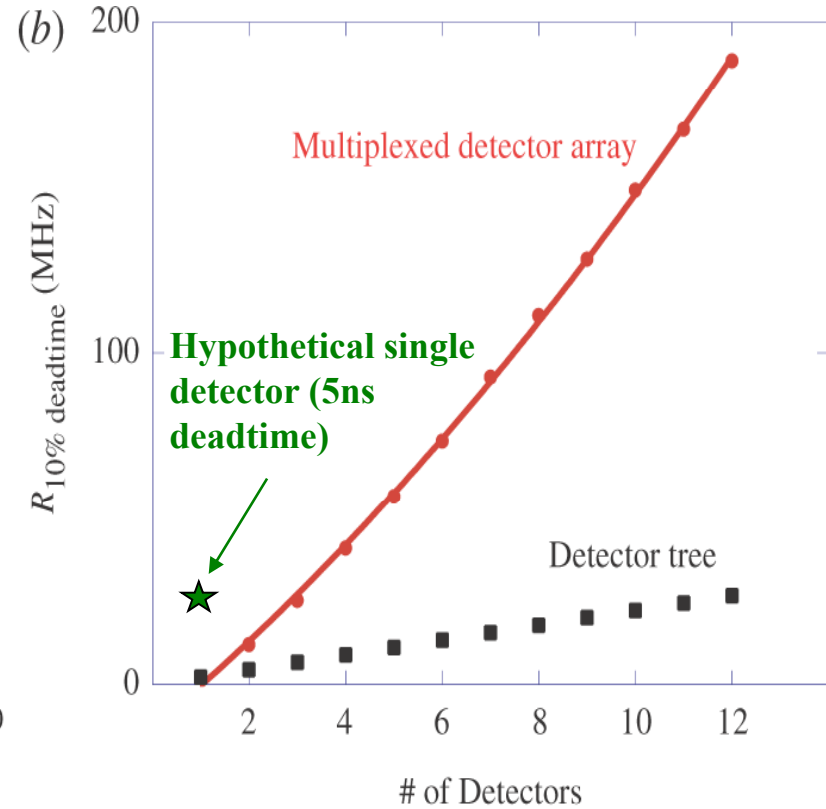
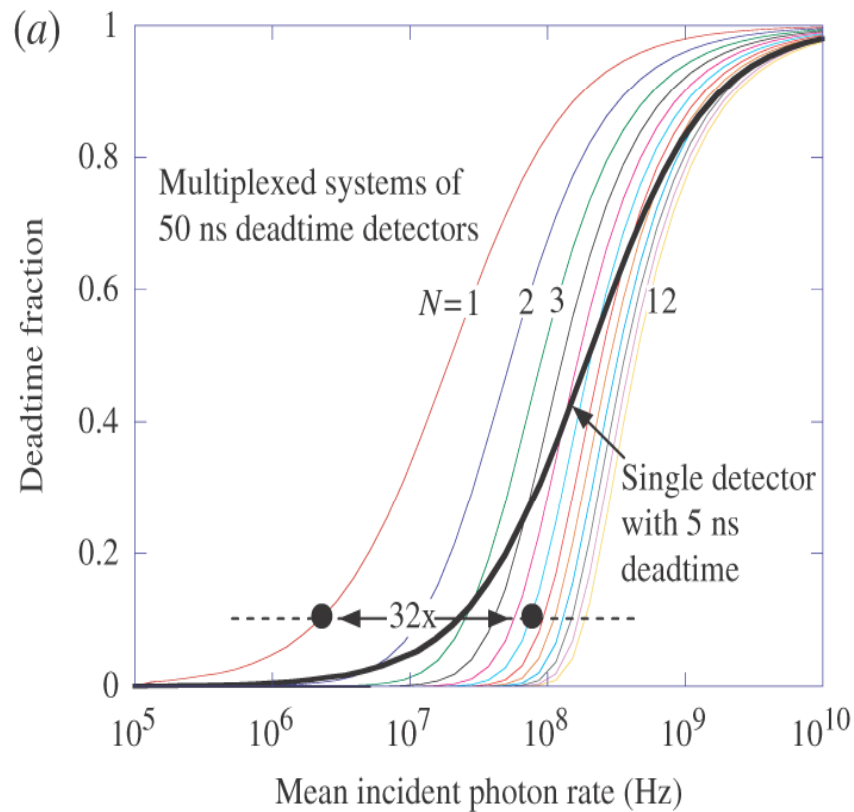
# Deadtime Model of Multiplexed Detector Array



zero switch transition time

# DTF and detection count rates

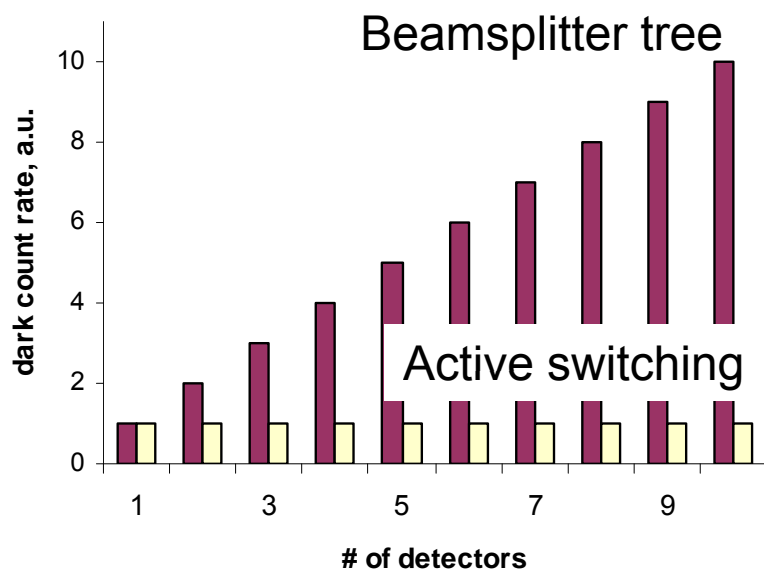
- In most cases an acceptable count rate is such that DTF < 10%



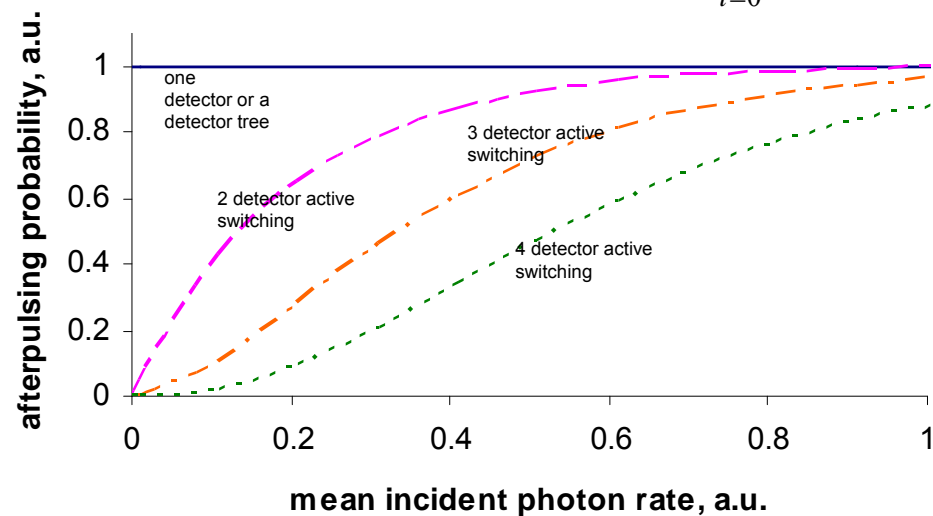
zero switch transition time

# Benefits Beyond Deadtime:

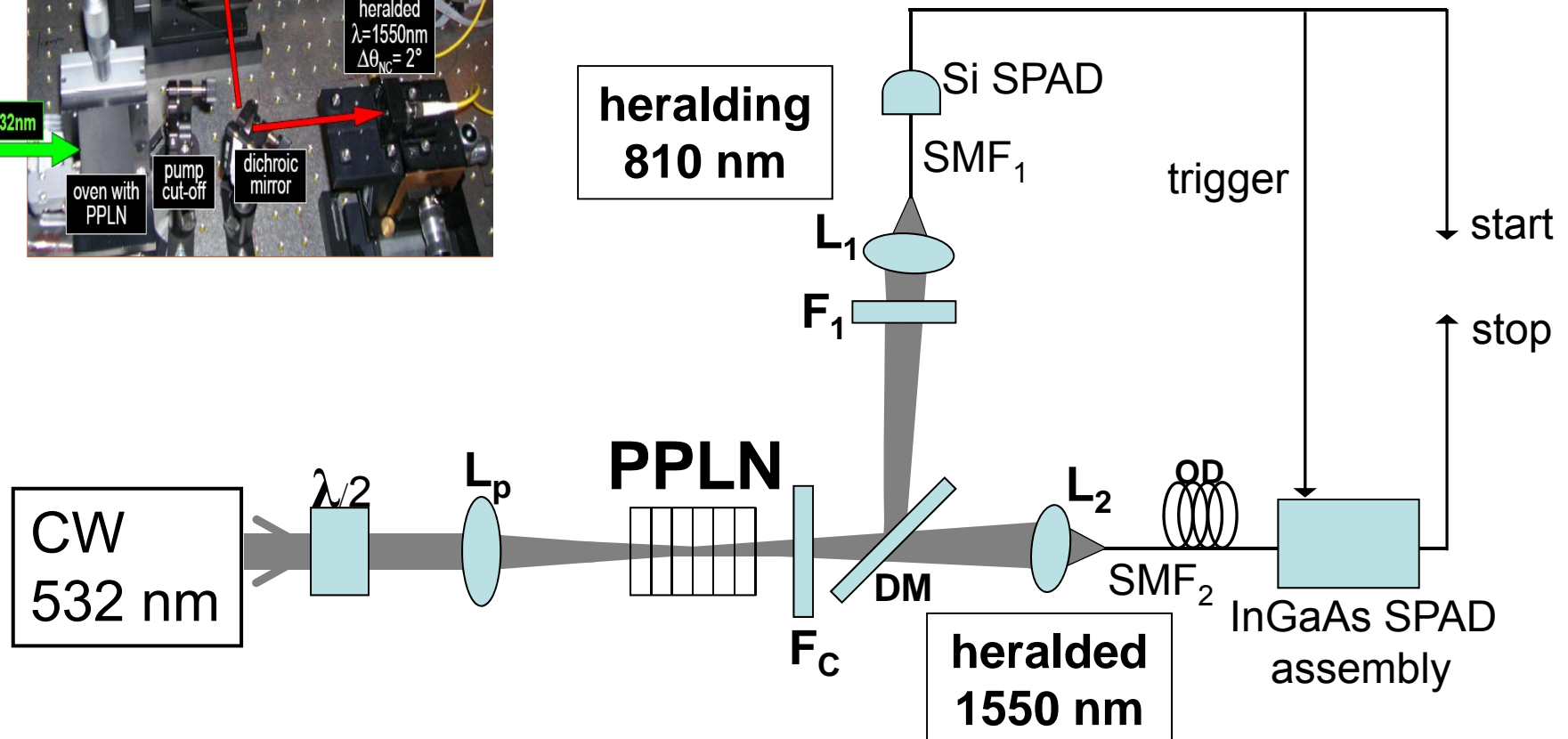
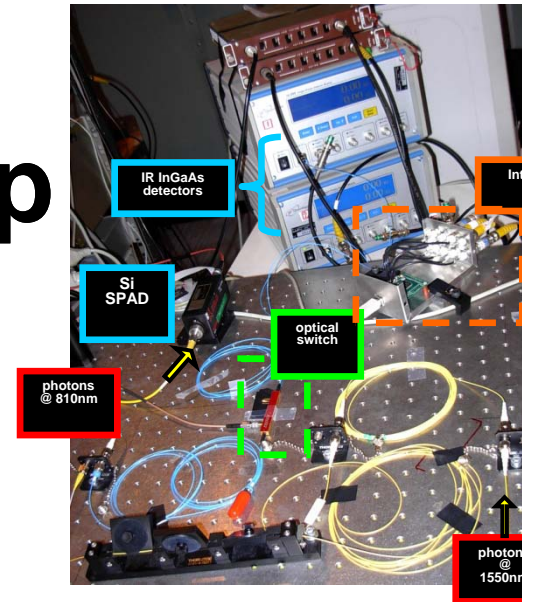
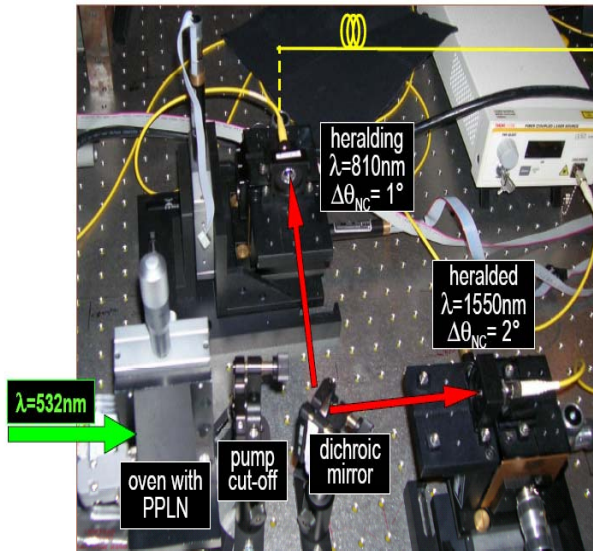
## dark counts & afterpulsing



$$P(n \geq N - 1) = 1 - \exp(-\lambda T_d) \sum_{i=0}^{N-2} (\lambda T)^i / i!$$

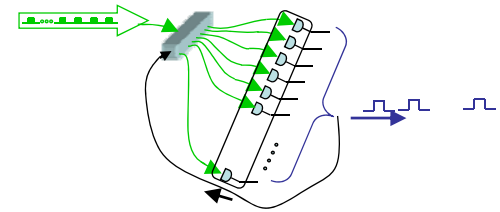


# Experimental setup



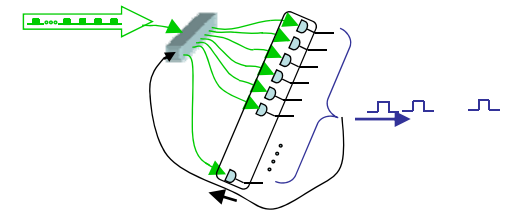


# Realism

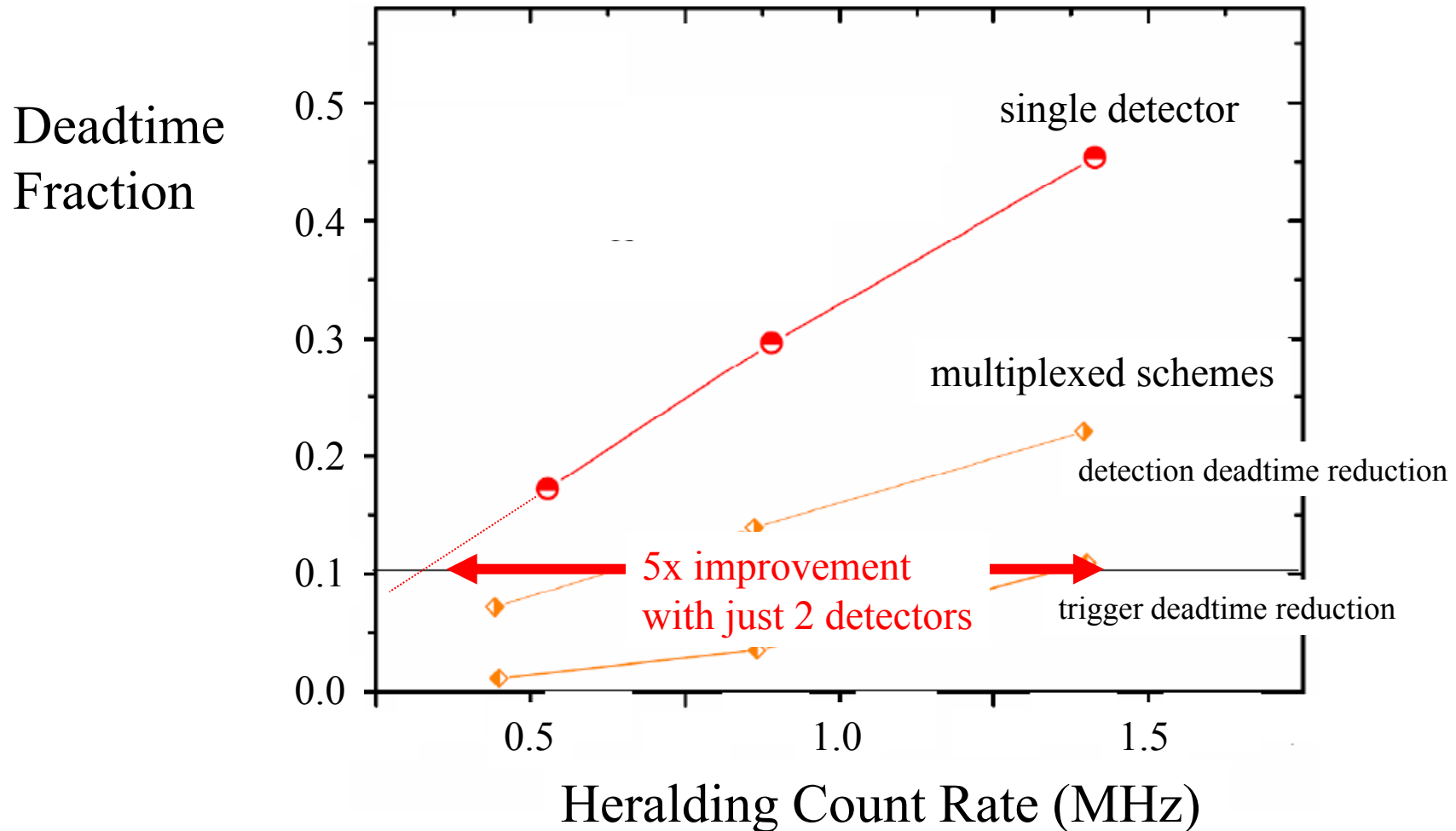


- Switch transition time  $\neq 0$   
includes:
  - Switch latency time
  - Switch propagation time
  - $T_{\text{switch}} \sim 100 \text{ ns}$  is practical for  $T_{\text{dead}} \sim 1 \mu\text{s}$
- Gate deadtime,
  - deadtime  $\neq 0$  for no detection
  - $T_{\text{gate}} \sim 200 \text{ ns}$  in our setup

# Latest Result



Trigger Electronics Deadtime:  
deadtime when it does not fire



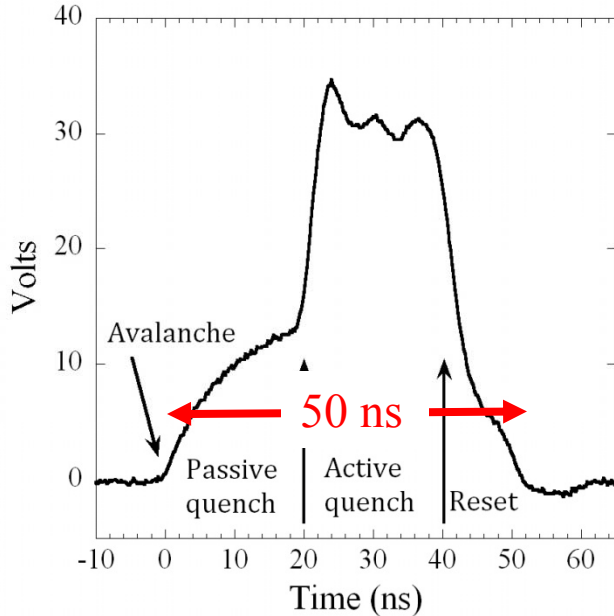
# APD- Advanced Electronics

Getting the most out of existing detectors

Joshua Bienfang  
Allesandro Restelli

# Active gating and quenching Si APDs

## Typical thick-Si-APD anode

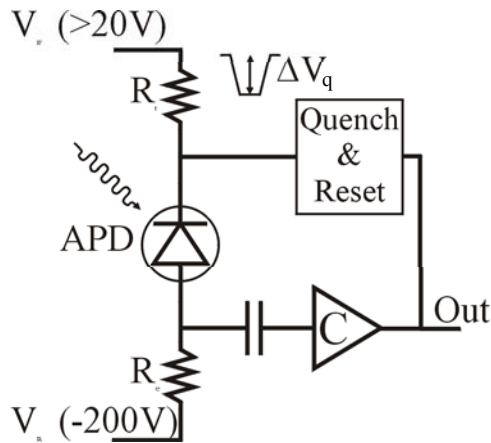


All useful information is acquired at onset of avalanche

- Combination of passive & active quenching  
→ latency in recovery time
- Any means to shorten recovery benefits count rate

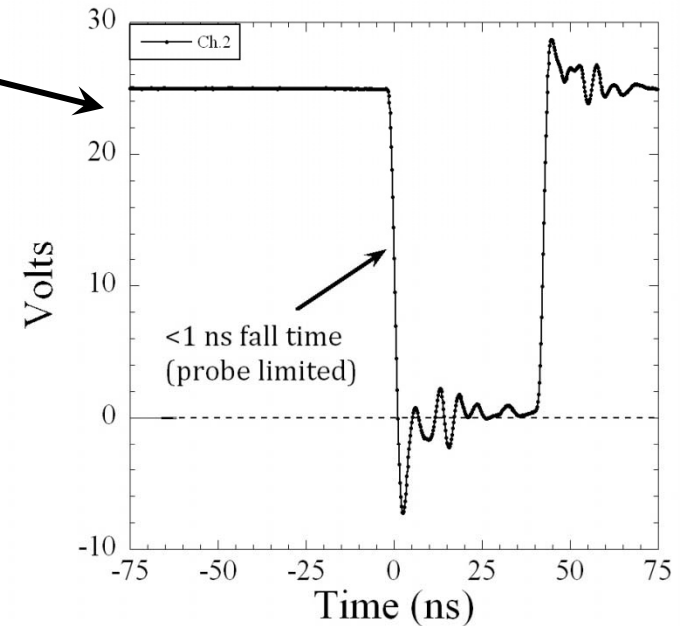
Sub-nanosecond control of Si APD bias can enable nanosecond gating, and reduce charge flow and after-pulsing.

Requires switching  $>20$  V in less than a nanosecond

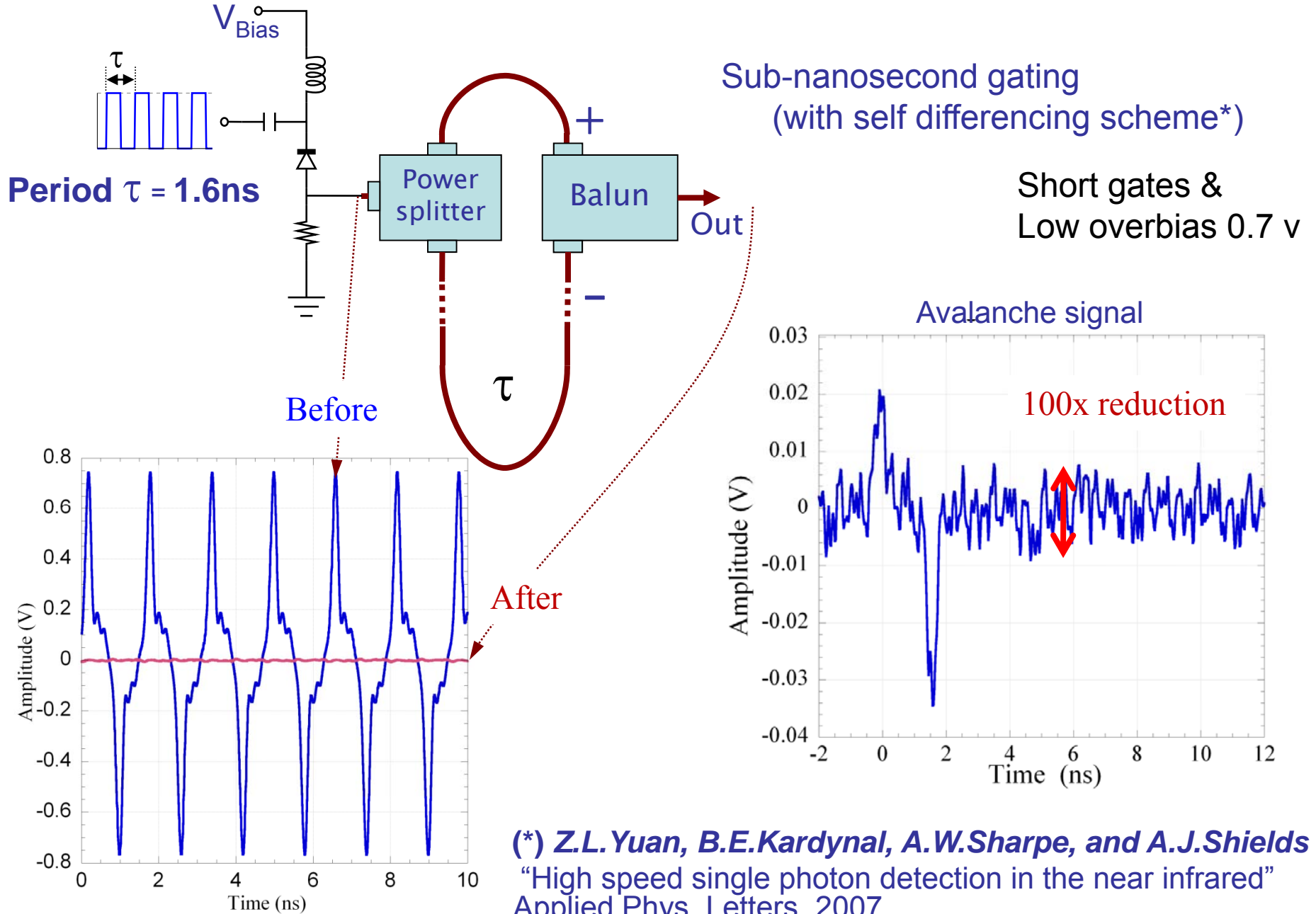


10x reduction in charge with quench 500 ps after avalanche

- GHz logic can provide  $<200$ ps propagation delay
- next issue: APD package high frequency compatibility



# Front-end electronics for Geiger-mode InGaAs/InP detectors (requires gated operation)

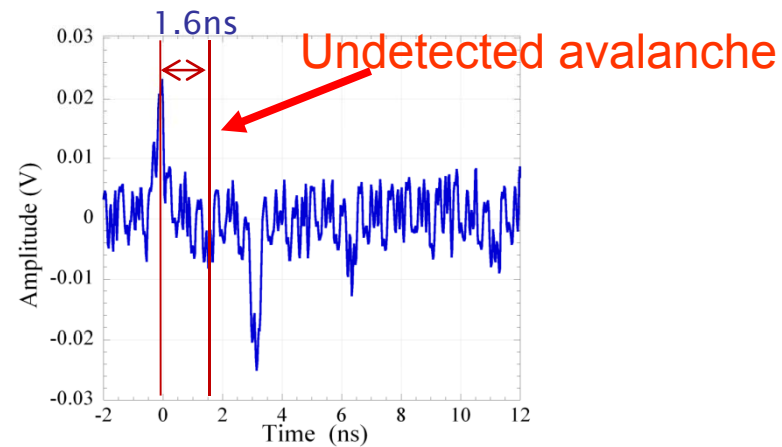
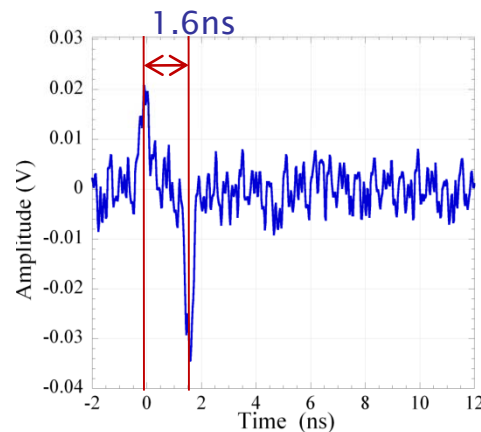


# Front-end electronics for Geiger-mode InGaAs/InP detectors.

Detection efficiency is limited by afterpulsing!

In addition...

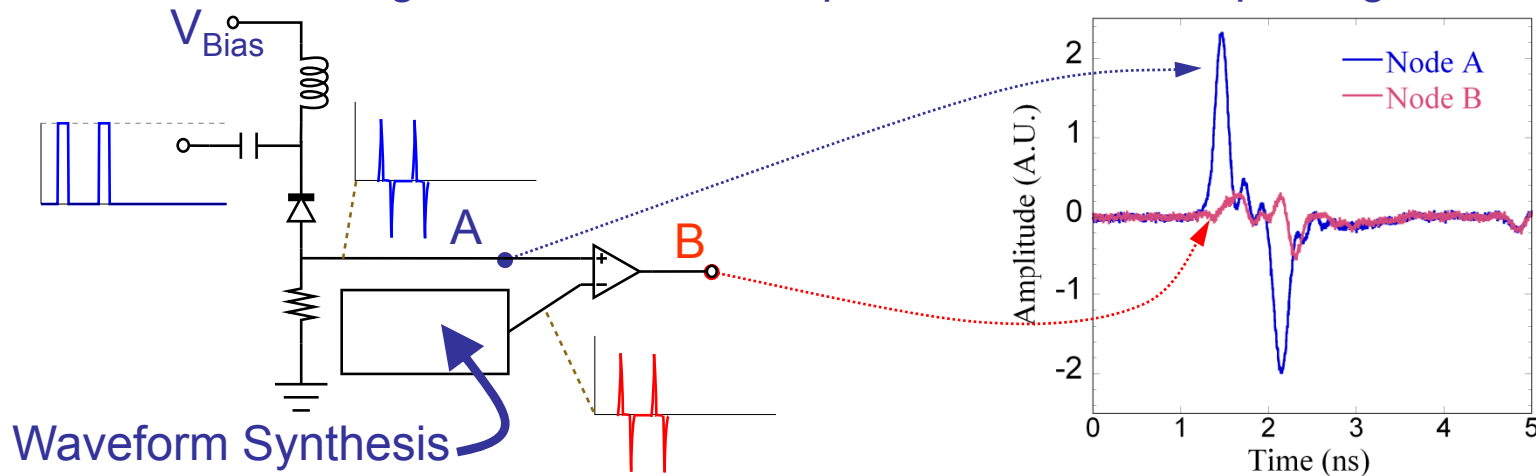
1. Avalanche current flow in adjacent gates can be masked ☹️



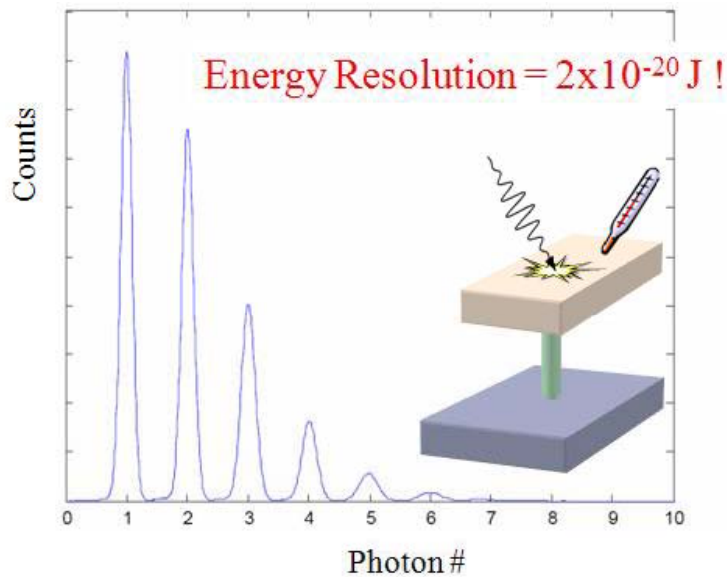
2. The gate *has* to be periodic:

- No possibility to introduce a dead-time longer than the gate period to reduce the afterpulsing.

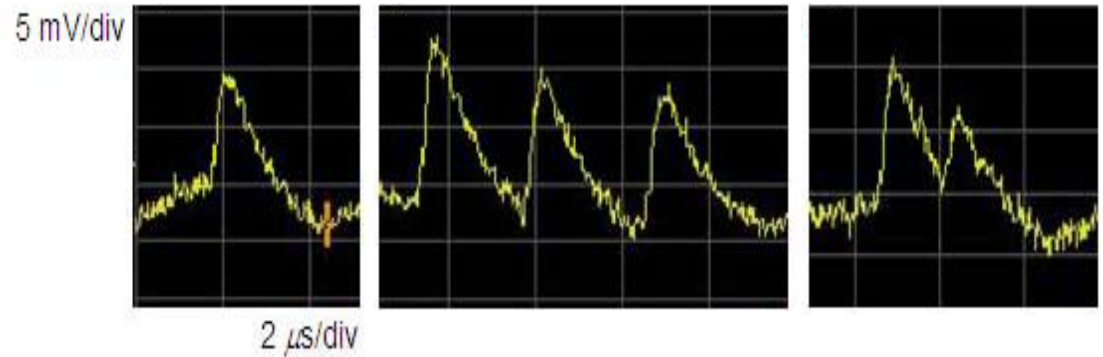
3. We are working on alternative setups to measure afterpulsing in the ns regime.



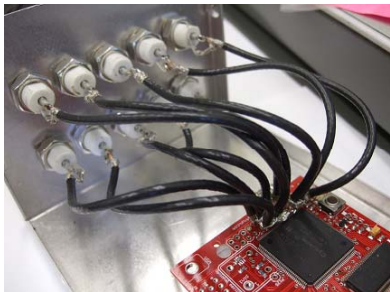
# Smart TES signal processing



No inherent deadtime:

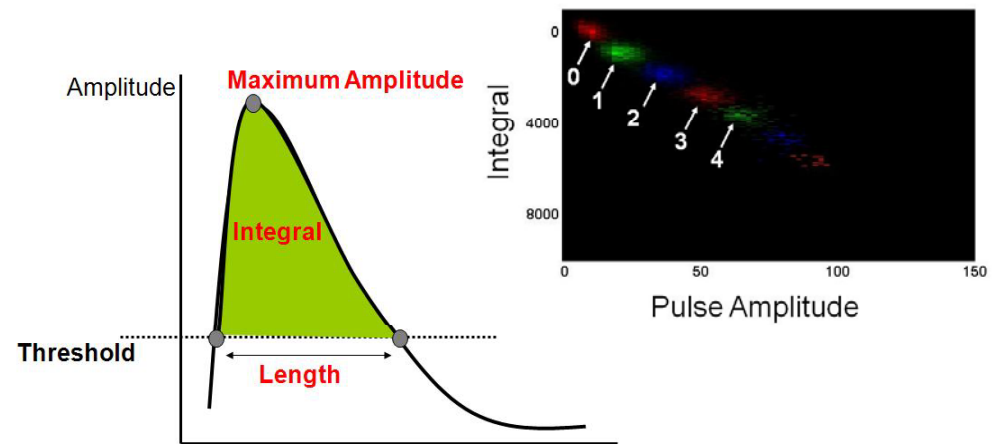


Deadtime-free processing:



Simple, cheap,  
high throughput  
signal processor

[physics.nist.gov/Divisions/Div844/  
FPGA/fpga.html](http://physics.nist.gov/Divisions/Div844/FPGA/fpga.html)

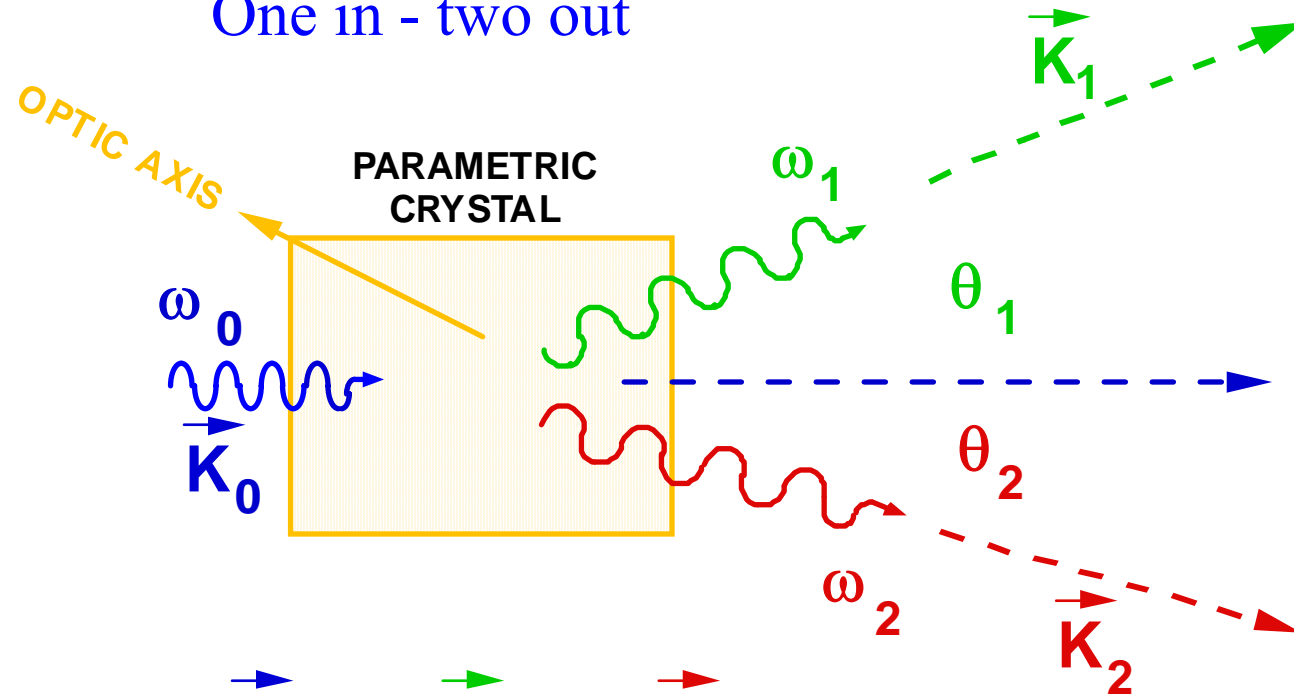


# Photon-Counting Metrology

Based on creating light two photons at a time

## Optical Parametric Downconversion

One in - two out

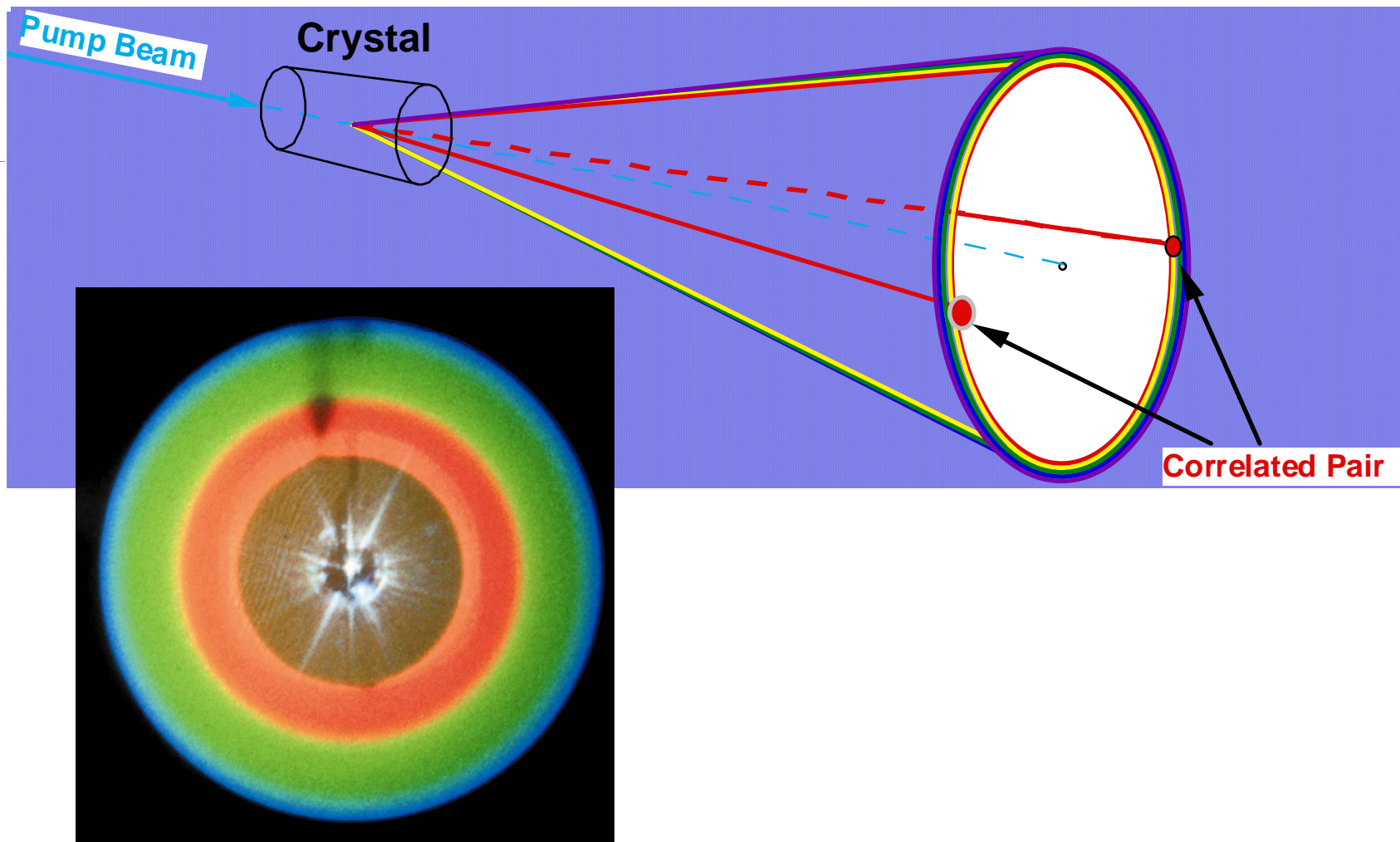


$$\vec{K}_0 = \vec{K}_1 + \vec{K}_2$$

$$\omega_0 = \omega_1 + \omega_2$$

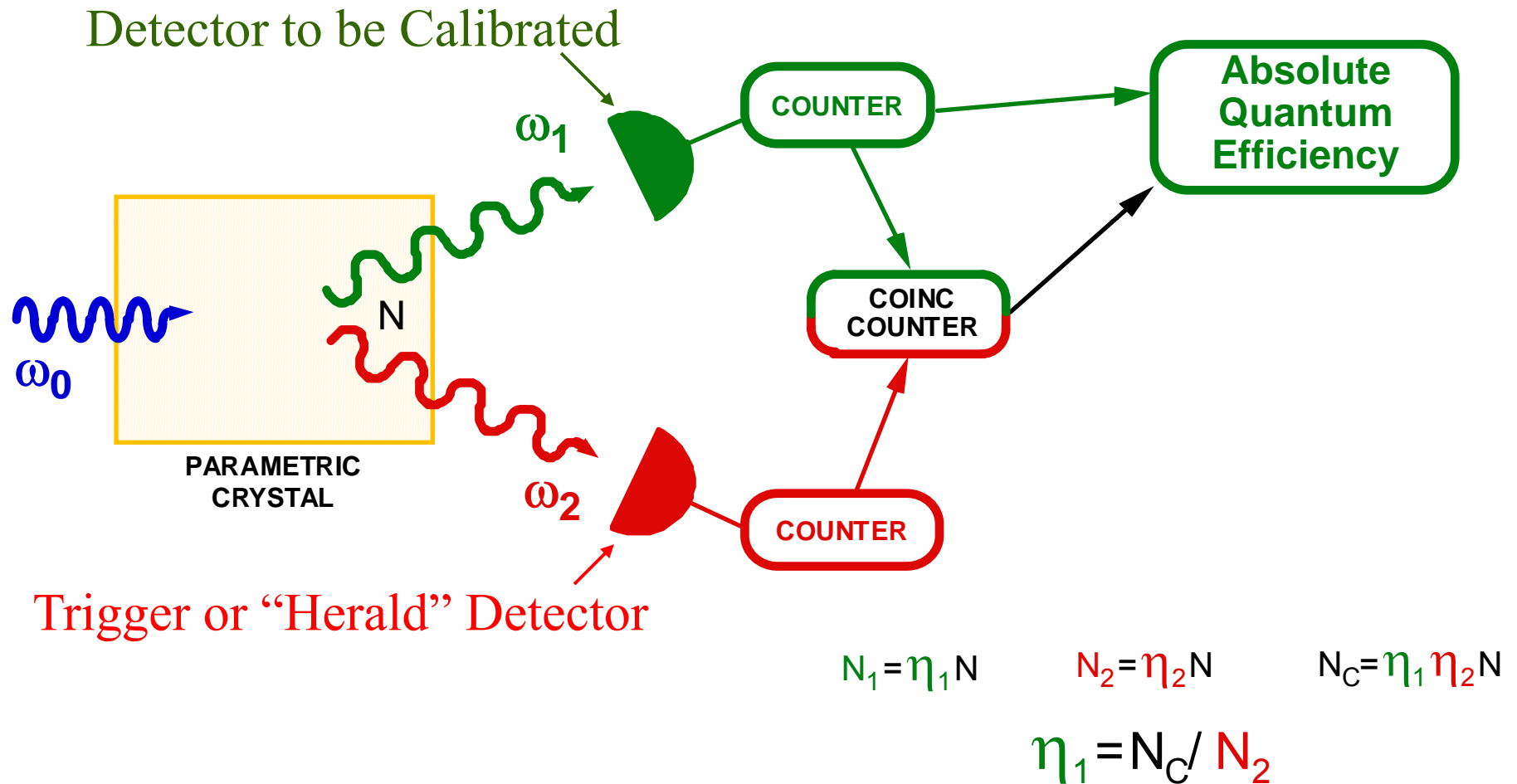


# Optical Parametric Downconversion

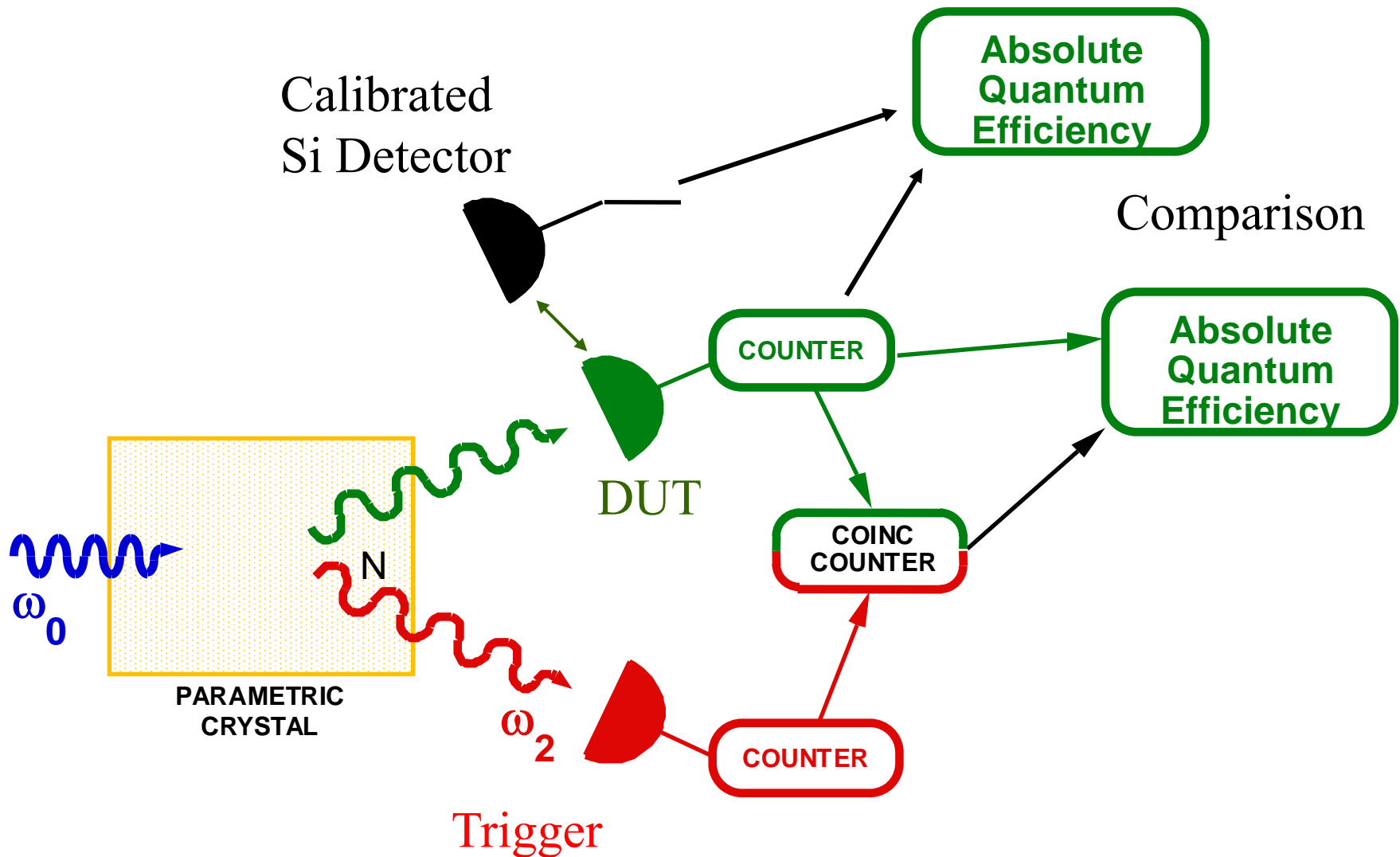


# Two-Photon Detector Efficiency Metrology

No External Standards Needed!



# Verifying the Method



# Turning Two-Photon Method into Metrology

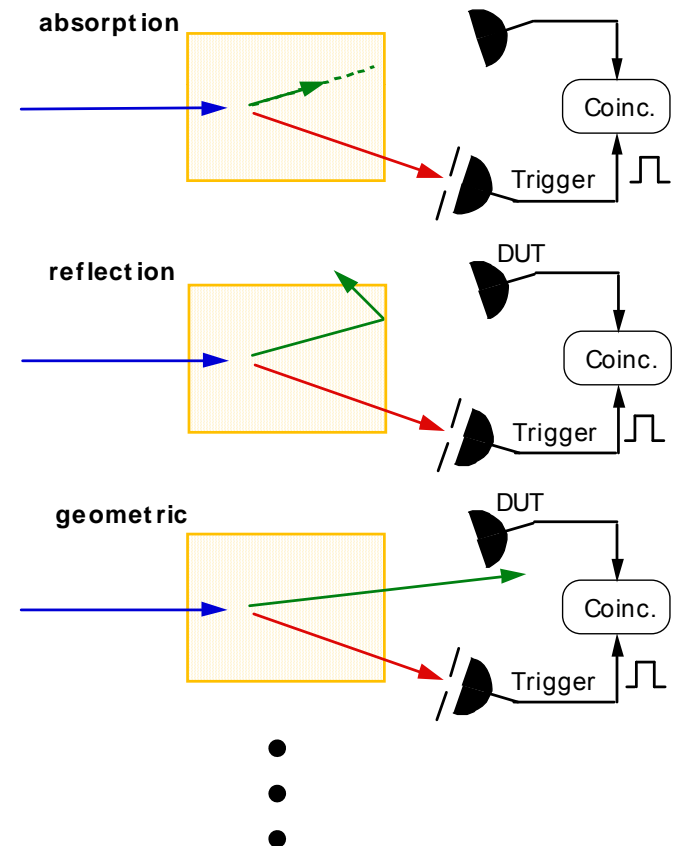
Sources of uncertainty:

**DUT Collection Efficiencies**

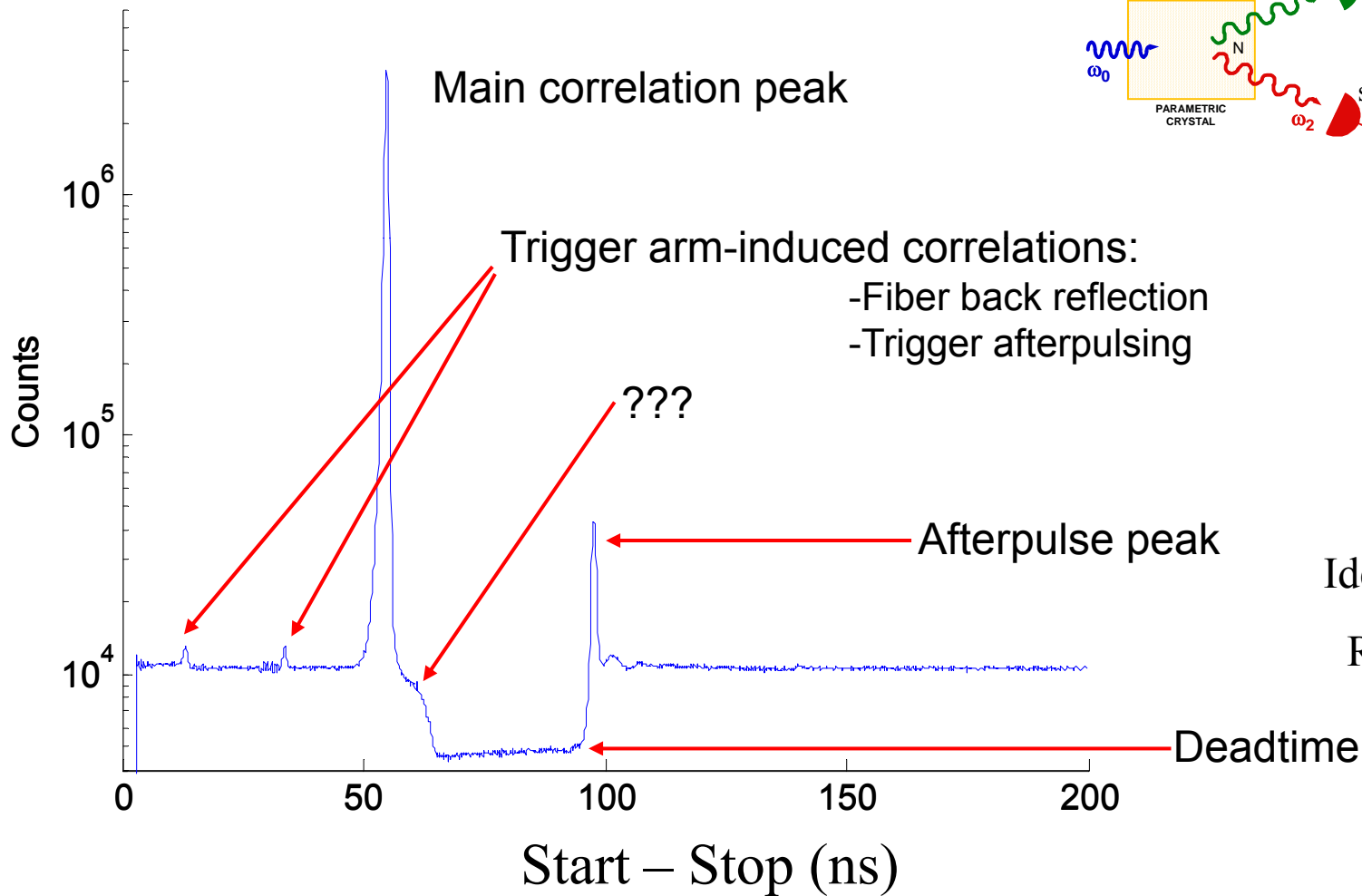
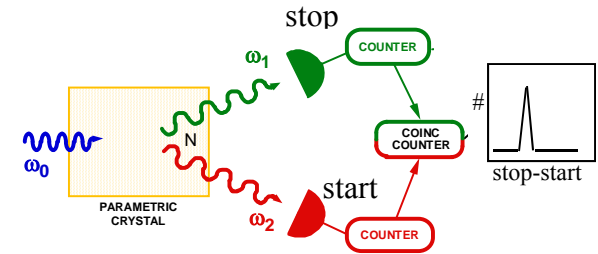
**Spatial**  
**Angular**  
**Spectral**

...

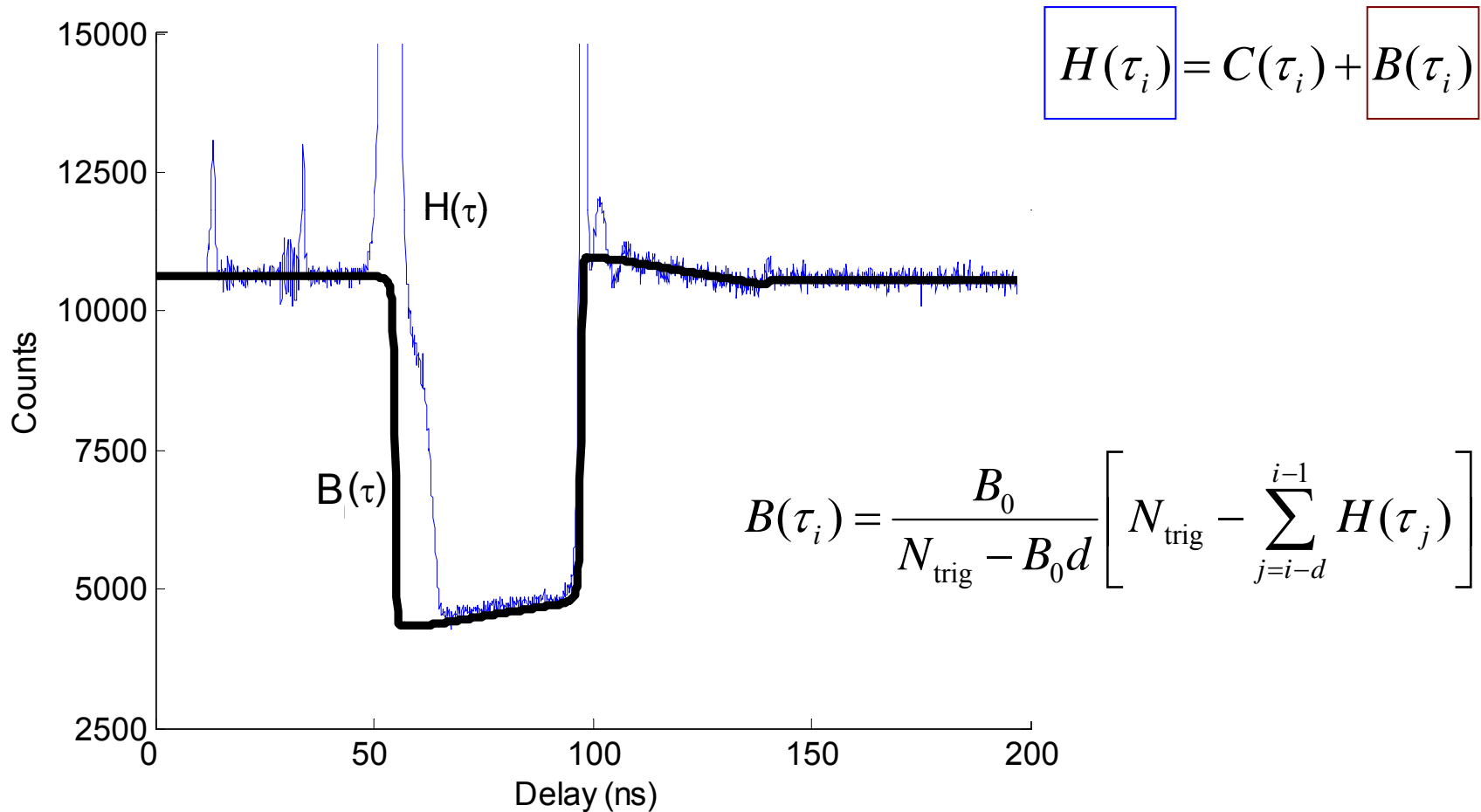
**Trigger counting**  
**Coincidence determination**



# Histogram and its Details



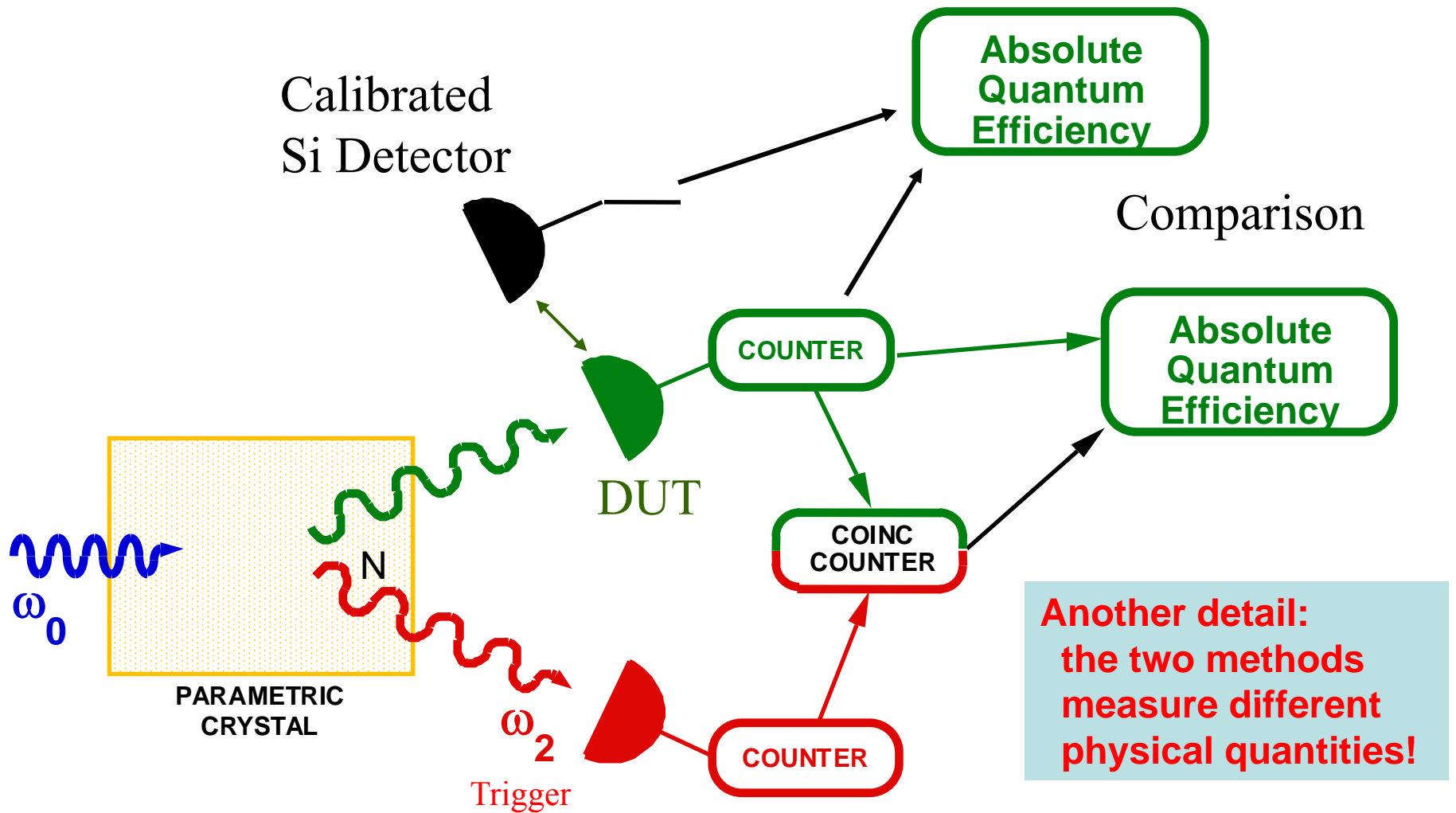
# Signal and Background (we can model it)



## Correlated photon calibration method uncertainty budget

Physical property	Value	Relative uncertainty of value (%)	Sensitivity	Relative uncertainty of DE (%)	
Crystal reflectance	0.09249	0.2%	0.1	0.02%	Optical losses
Crystal transmittance	0.99996	0.009%	1	0.009%	
Lens transmittance	0.97544	0.0027%	1	0.0027%	
Geometric collection (raster scan)	0.9995	0.05%	1	0.05%	
DUT filter transmittance	0.9136	0.1%	1	0.10%	
Trigger bandpass to virtual bandpass/wavelength				0.07%	
Histogram background subtraction				0.03%	Histogram
Coincidence circuit correction	0.0083	10.0%	0.008	0.084%	
Counting statistics				0.08%	
Deadtime (due to rate changes with time)				0.02%	
Trigger afterpulsing	0.0025	25.0%	0.003	0.06%	Trigger
Trigger background, & statistics	175000	0.3%	0.035	0.01%	
Trigger signal due to uncorrelated photons	0	0.07%	1	0.07%	
Trigger signal due to fiber back reflection	0.00202	1.60%	0.002	0.003%	
<b>Total</b>				<b>0.18%</b>	

# Verifying the Method





# Comparison/Results

- NIST implementation of High Accuracy SPD Calibration methods

<b>Method</b>	<b>Absolute uncertainty</b>
Two-photon	0.18%
Substitution	0.17%

- Uncertainty of each individual comparison:

**0.25%**

- Overall mean difference between the two methods:

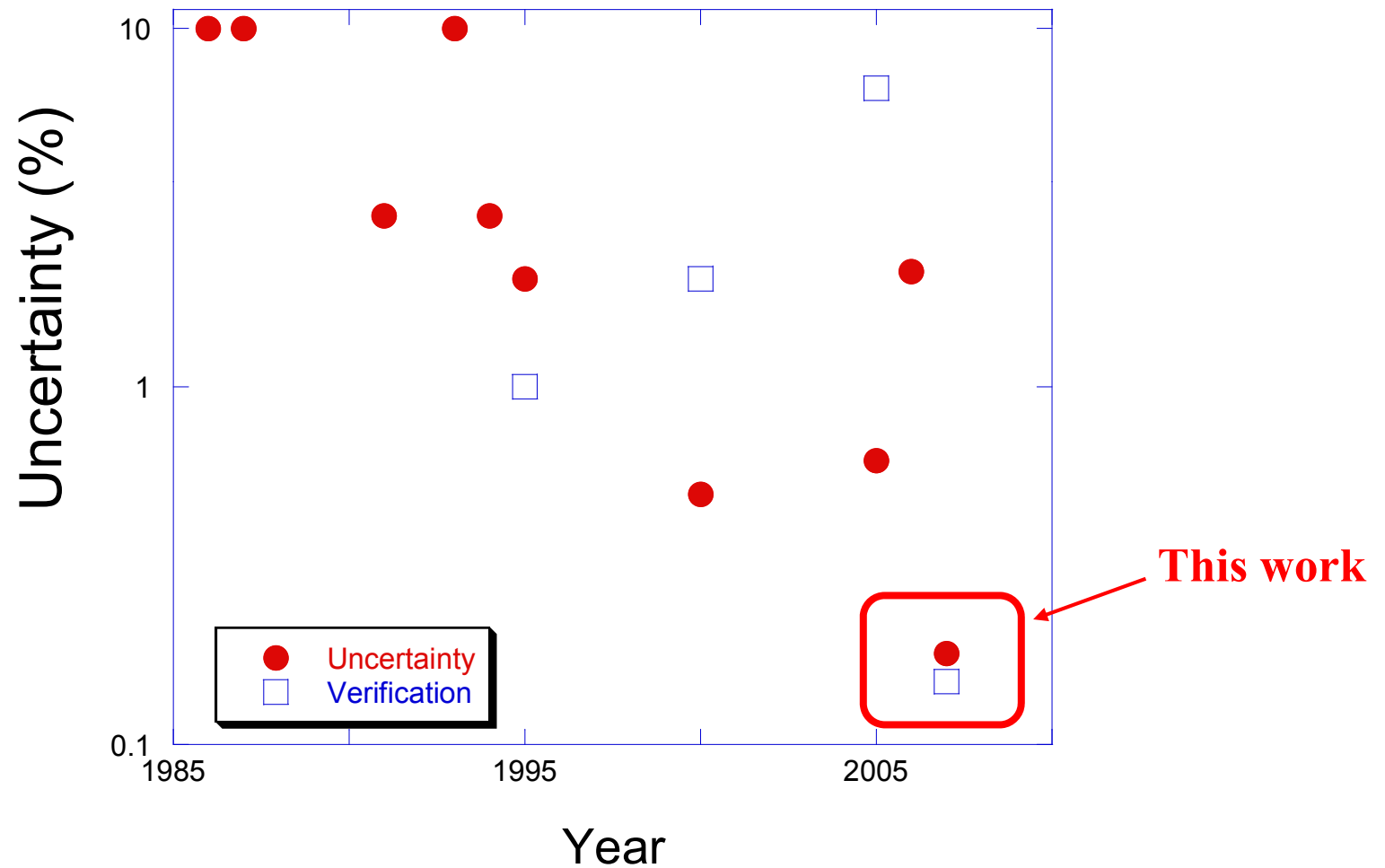
**0.15%±0.14%** ( $\eta_{\text{sub.}} > \eta_{\text{2-photon}}$ )

Highest accuracy verification of the 2-photon method yet achieved

# 2-Photon Metrology Progress

Year	1 <sup>st</sup> author	Uncertainty of		External Comparison
		Method	Verification	
1970	Burnham	~35%		Calibrated lamp
1981	Malygin	-		
1986	Bowman	~10%		
1987	Rarity	~10%		HeNe + attenuation
1991	Penin	> 3%		
1993	Ginzburg	~10%		Published values
1994	Kwiat	~3%		
1995	Migdall	< 2%	1%	Calibrated Si Detector
2000	Brida	~0.5%	2%	Calibrated Si Detector
2005	Ghazi-Bellouati	1.1, 0.62%	6.8%	French cryoradiometer
2006	Wu	2.1%		
2007	Polyakov	0.18%	0.15%	Calibrated Si Detector

# Metrology Progress



# Single Photon Metrology

Goal: 0.5% photon counting calibration to the masses

- Metrology
  - Correlated Photon Method
  - Transfer Standard Method
- Compared the two
- Lessons Learned
- Dissemination Effort
  - High-gain low-noise transfer standard

# Transfer standard design

Goal: 0.5% uncertainty  
disseminated to users

Desires: Bridging photon-counting to analog levels

- Detector:
  - Visible
  - Stable response vs temperature
  - Spatially uniform response
  - Low Noise for photon counting levels
- Amplifier
  - High gain for photon-counting levels
  - Lower gain for analog calibration levels
  - Thermal stability
  - Gain stability & precision for calibration ease

# Transfer standard design

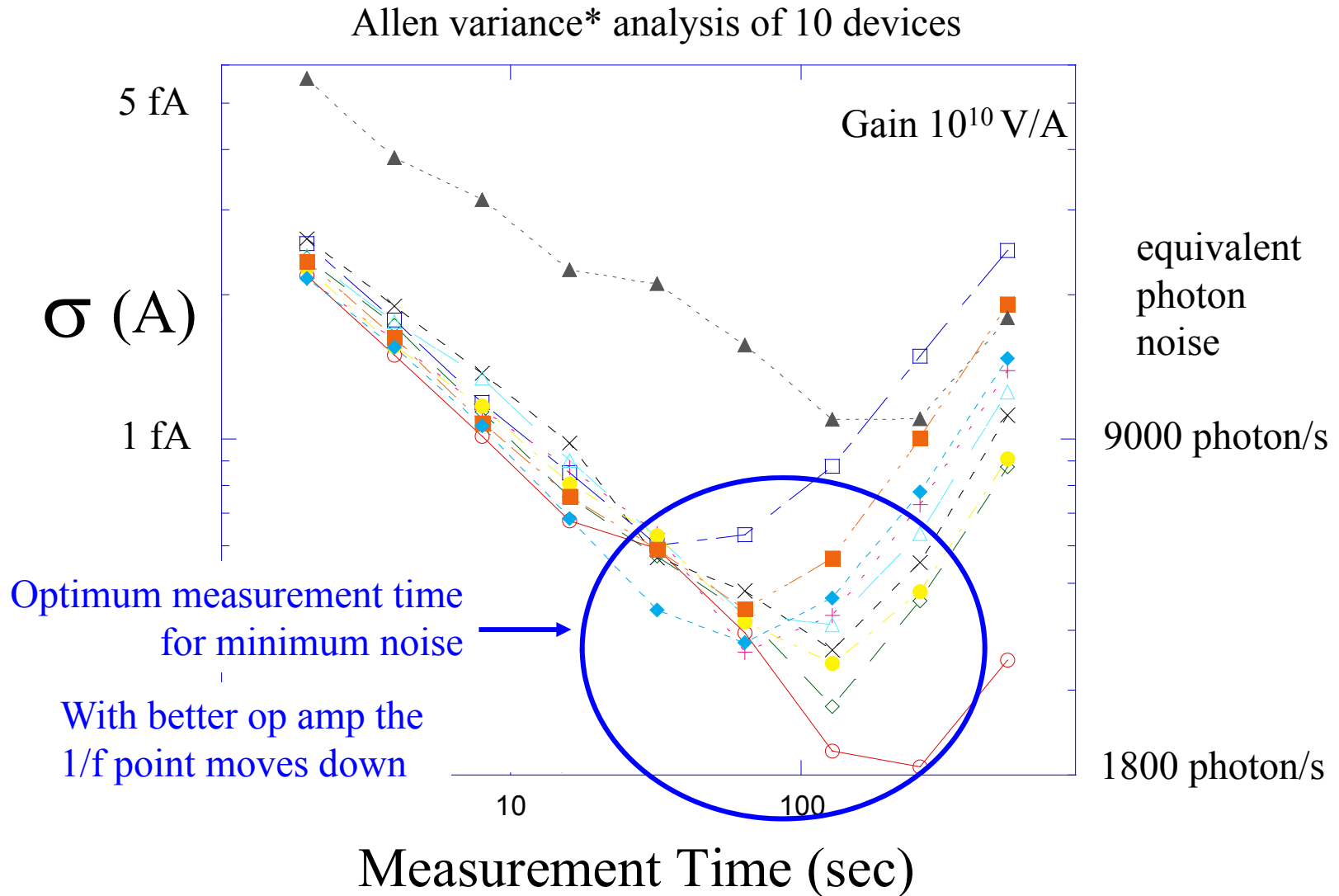
## Si detector/amplifier

Goal: 0.5% uncertainty  
disseminated to users

- Detector: Si 5.8x5.8 mm Sapphire window (Hamamatsu S2592-04)
- Spatial response uniformity: 0.1%
- Cooled detector for
  - high shunt resistance:  $\sim 5 \text{ G}\Omega$
  - high gain:  $10^7, 10^8, 10^9, 10^{10} \text{ V/A}$
  - low noise: sub-fA
- Temperature stabilized for
  - low drift 0.1C gives  $< 0.1\%$  response stability
- Gain: high precision nominal levels
  - $10^7, 10^8 \text{ V/A}$ : 0.01% & 10 ppm/C
  - $10^9, 10^{10} \text{ V/A}$ : 1% & 100 ppm/C
- Gain compatible with
  - Photon-counting levels ( $< 0.1 \text{ pW}$ ,  $10^6 \text{ photon/s}$ ,  $10^9 \sim 10^{10} \text{ V/A}$ )
  - Analog calibration levels ( $> 0.1 \text{ }\mu\text{W}$ ,  $10^7 \sim 10^8 \text{ V/A}$ )



# Transfer standard testing



\* Deviation of adjacent differences:  $\sigma_y^2 = \frac{1}{2} \langle (y_{i+1} - y_i)^2 \rangle$

# Can we get to 0.5% goal?

- For 100 s noise  $\sim 5000$  photon/s  
Signal of  $10^6$  photon/s allows 0.5% uncertainty
- Scale transfer 0.1% (combined uncertainty)
- Gain range changes: 0.01% (gain 7,8) 1% (gain 9, 10)
- So far so good
- Further work
  - Better op amp temperature dependence
  - Frequency response for possible AC operation for lower noise
  - Gain range tolerance tests
  - Calibration
- Robust transfer standards for dissemination to user community

Thanks to IARPA for funding



**Redefining optical power traceability:  
Bridging the gap from  
single-photons to tera-photons**

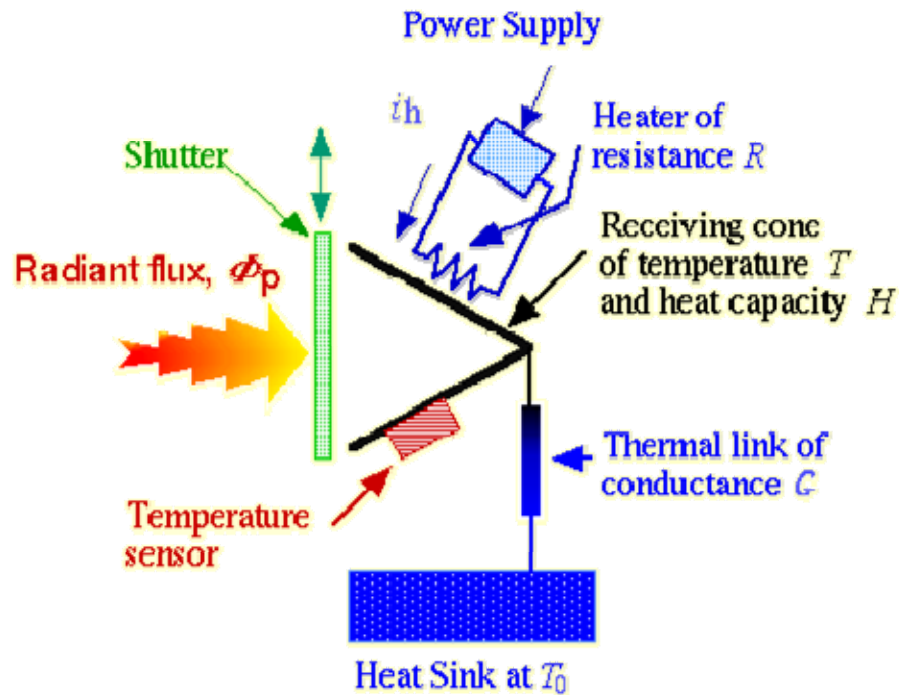
Sae Woo Nam

John Lehman, Alan Migdall, & Rich Mirin

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# Radiometry

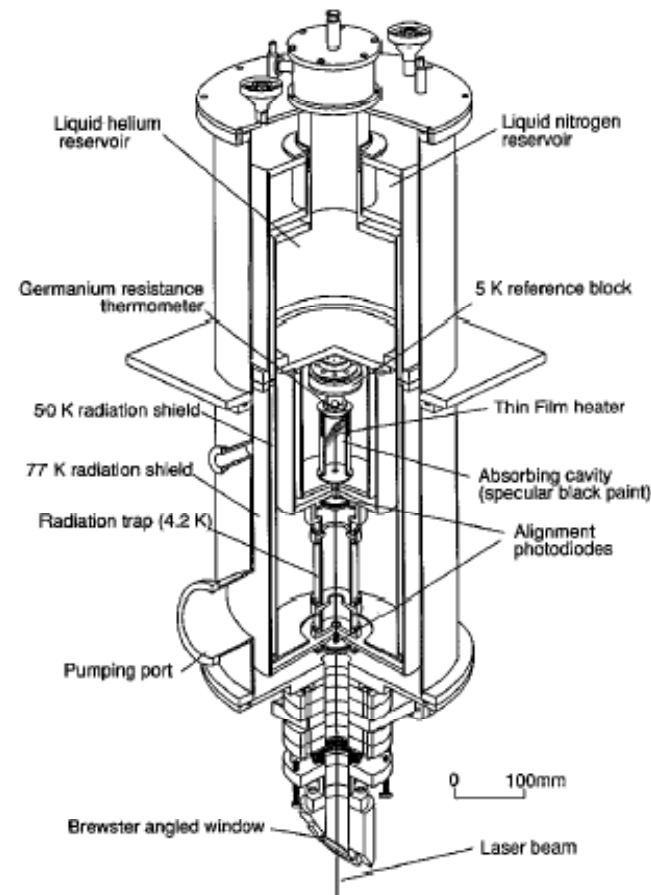
# Electrical Substitution Radiometry



From NIST Technical Note 1421, A. Parr

**Optical Power = Electrical Power**

High-Accuracy  
Cryogenic  
Radiometer  
(HACR) 1980s



Laser  
Optimized  
Cryogenic  
Radiometer  
(LOCR)  
1990s



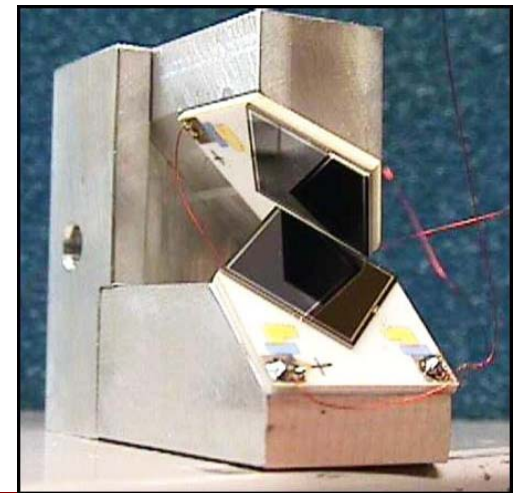
*Redefining optical power traceability*

## Details:

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- **“World’s best” cryogenic radiometry: Uncert = 0.01%**
- **Primary standards (cryogenic radiometers) operate over limited range and relatively “high” powers**
  - Typical operation is  $\sim 100$   $\mu\text{W}$  to  $\sim 1$   $\text{mW}$
  - Dissemination to customers degrades due to transfer standard limits  $\sim 1\%$
  - Optical power traceability has the poorest uncertainty of major measurands
- **Difficult to link the lower range of optical powers used by industry to primary standards**

**No formal connection between classical methods to measure optical power and new methods to measure single photons**



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*Redefining optical power traceability*

# What could the future look like?

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**Return to a “standard candle” –  
Single-photon devices that provide  
Single-photons on demand**

- **Dial in the rate**
- **Dial in the wavelength**
- **“Known optical powers” on demand  
to calibrate devices**

**Change the way optical power is disseminated!!**

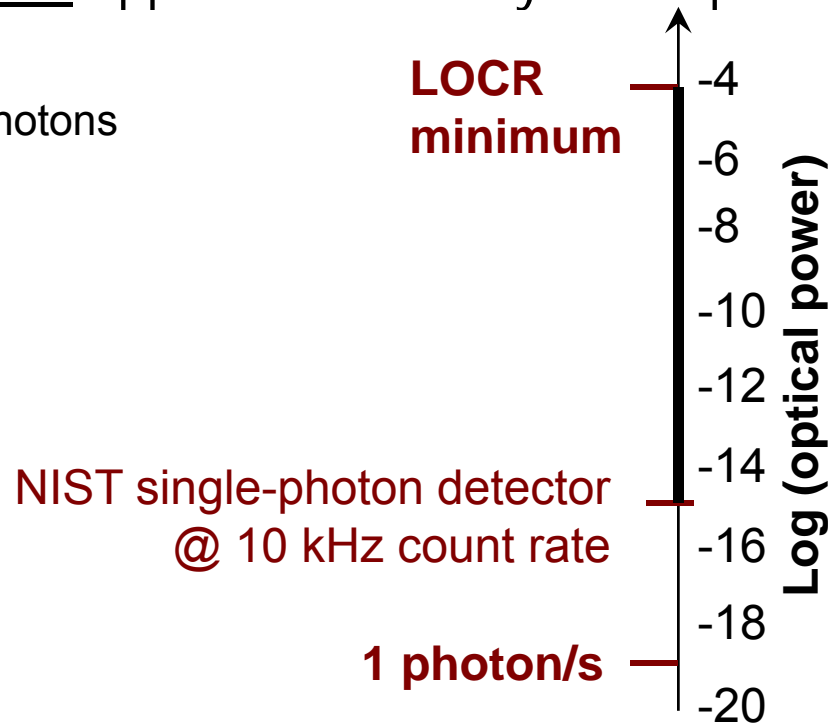
# Why is it hard? The power range is enormous

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## 11 order-of-magnitude gap

between cryogenic radiometry and single photonics assuming ideal application of today's best photon counting technology

For  $\lambda = 1 \mu\text{m}$  photons



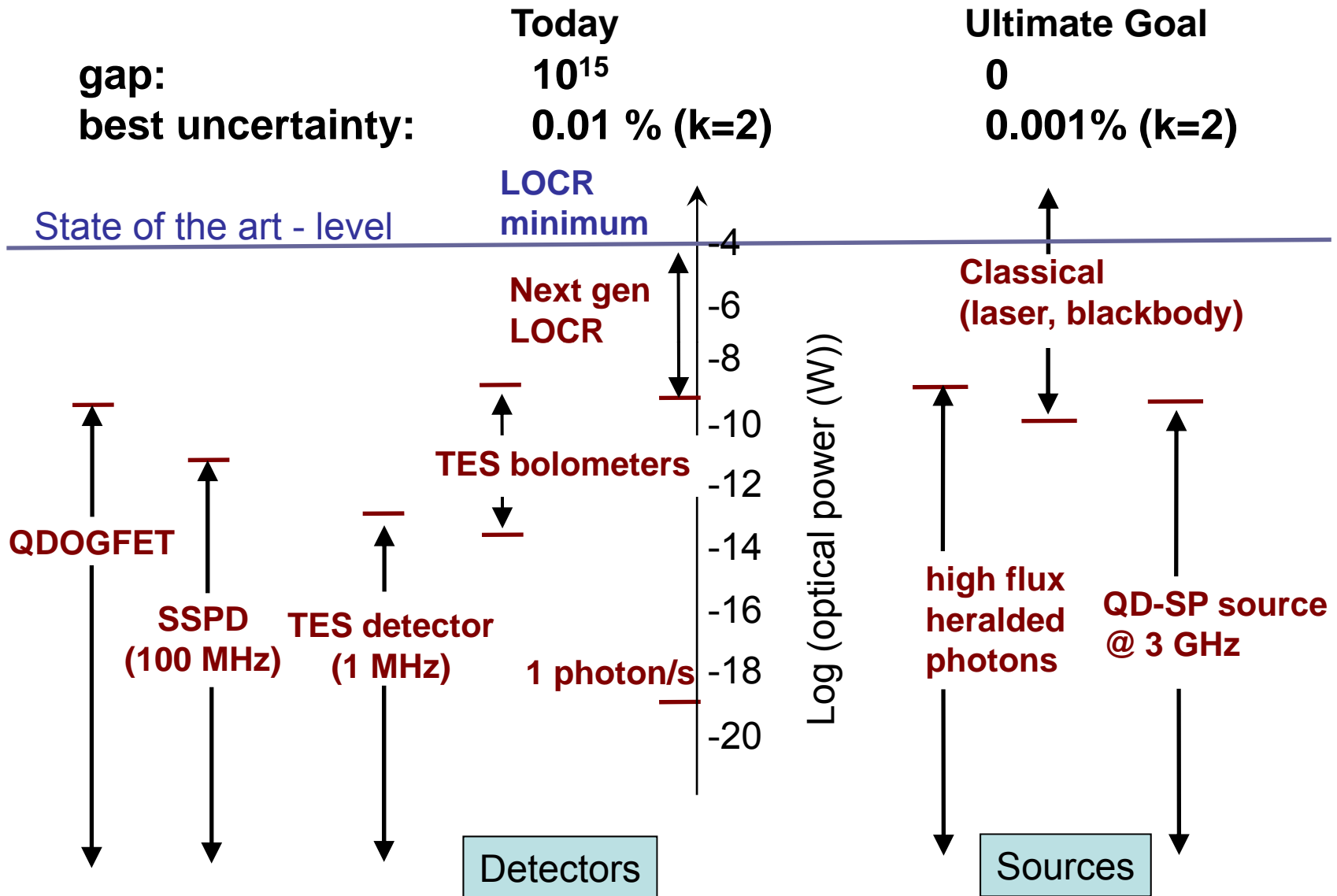
In 2007, first attempt to close the gap was done by comparing the calibrations done classically and with a heralded photon source

**No traceability between conventional radiometry and photon counting**

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*Redefining optical power traceability*

# How do we bridge? Overlap power ranges



*Redefining optical power traceability*

# **Simple and Inexpensive, Fast Time-Resolving Multichannel Coincidence Board**

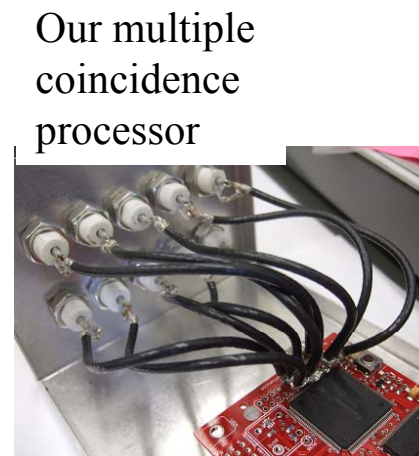
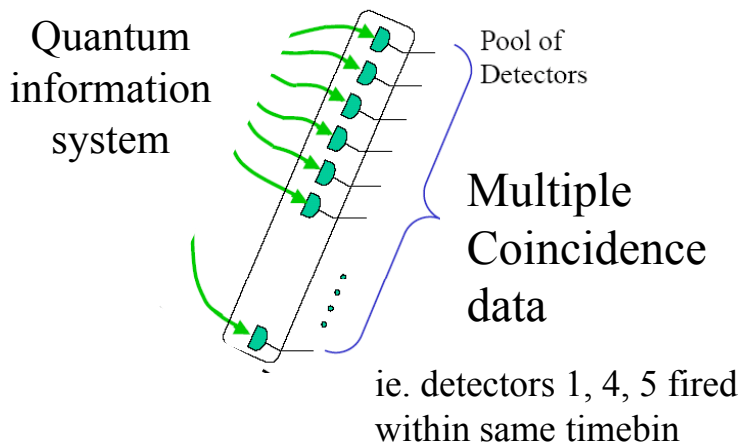
Sergey Polyakov

Sae Woo Nam

Alan Migdall

# What?

- Real-time recording and statistical processing of electrical pulses (*on-board processing*)
- Records and processes multiple-channel inputs
- Looks for coincidences between 2 or more channels (*any and all combinations detected*)





# What's new?

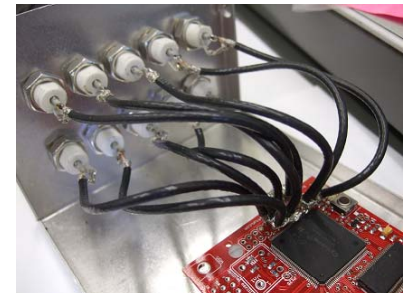
- Scalability to many channels <<big deal
  - Existing:
    - 2 channels coincidence boards run in parallel for more than two channel coincidence
- All n-fold coincidences can be detected (flexibility) <<big deal
  - Existing:
    - Fixed n-channel coincidence detection
    - No real time multicoincidence processing
- Single-chip design (allows very low cost)
- Internal clock synced to external experiment

# How it works

- FPGA & software:
  - Pulse edge detection
  - Synchronous timer
    - internal FPGA timer synchronized to external experiment timer
  - Many input channels
    - Inherent scalability for N-coincidence detection
  - High timing resolution
  - On-board processing:
    - Picks out multicoincidences
    - Transfers only desired events to pc
- Implemented with existing design board with:
  - Plug & Play USB2 connectivity with transfer rates to PC of >2 MB/s

*Solves the multiple-coincidence detection problem*

*Solves the data transfer problem*





# Limitations of our approach

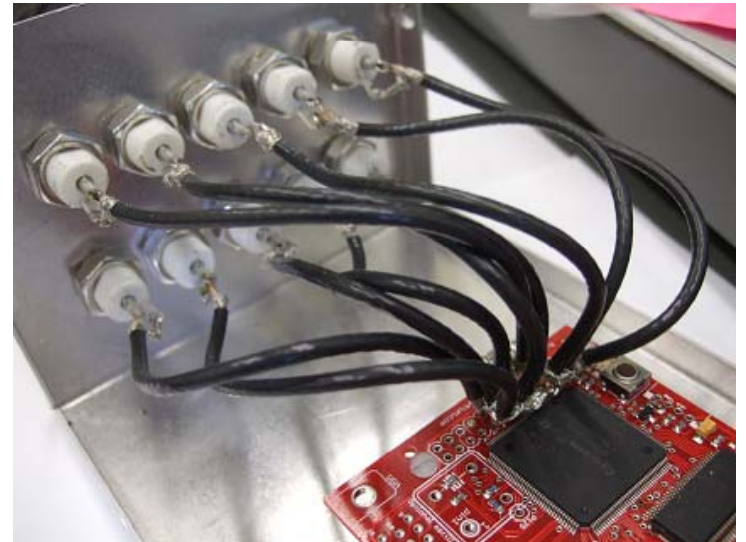
- *The time stamping rate limited by fastest toggle time of FPGA.*

*Current prototype: ~6.5 ns.*

- *Underway: SBIR pushing to ~1 ns*

# Multi-channel coincidence processor summary

- Novel technology for multiple channel coincidence detection
- Advantages
  - Scalable
  - Flexible
  - External synchronization
  - Robust (hardware is disposable)
  - Compact
  - Cost
- Dissemination-
  - [physics.nist.gov\FPGA](http://physics.nist.gov\FPGA)



# System how to documentation

NIST Quantum information technology ... Data Acquisition Platform

Physics Laboratory  
Optical Technology Division

NIST  
National Institute of Standards and Technology

Home Research Areas Products And Services Meetings Site Map

[Version History](#) | [Disclaimer](#)

## Simple and Inexpensive Data Acquisition Platform

The Data Acquisition Platform project allows one to build their own data acquisition instruments that collect and, if necessary, statistically process data in real time and send the results to a standard PC via the USB-2 interface. The collected data can be accessed in real time by a user's application. While in our case, the effort was started to build instruments that perform pulse time stamping and multiple coincidence detection, relevant to single photon detection and statistical analysis, particularly for quantum information experiments, users can easily modify the data collection algorithm and create a wide range of custom instruments. Because data transfer protocols are already written and debugged, users can significantly decrease development time. At the same time, the project requires a minimal investment in hardware, namely a commercially available FPGA testing board that requires no significant modifications. The only necessary modification is wiring the board to the experiment, which usually involves basic soldering.

The platform is based on a [Xylo-EM board](#) and consists of four parts:

1. our FPGA firmware, that incorporates a data collection algorithm that can be application specific and a program that realizes a data transfer protocol (operates a Cypress FX2 chip that provides USB2 connectivity).
2. Cypress FX2 firmware (provided with the Xylo-EM board) that supports the ez-usb driver run by the host computer – compatible protocol for USB2.
3. our C code (mid-level driver) that receives the acquired data and prepares it for an end-user application in real time and
4. end-user custom code in your favorite computer language that processes and/or graphs the received data.

```
graph TD
    Detectors[from detectors] --> ADC[ADC if needed]
    ADC --> FPGA
    subgraph FPGA
        Measurement --> DataStorage[Data storage]
        DataStorage --> FPGA_FX2[FPGA-FX2 interface]
    end
    subgraph PC
        FX2_chip[FX2 chip] --> USB2[USB2 and EZ-USB driver]
        USB2 --> MidLevel[Mid-level driver]
        MidLevel --> HighLevel[High level end-user code]
    end
    FPGA_FX2 --> USB2
```

Fig. 1. Block diagram of the platform (data collecting, storage, FPGA-FX2 interface, FX2 multi-directional interface, EZ-USB driver, mid-level driver, high-level end user (visualization) software. To record an analog signal, an Analog-to-Digital Converter (ADC) can be used.

Figure 1 shows the system design. If an existing instrument is used, only the end-user code needs to be customized to match the application. If a new instrument is built, both FPGA firmware (data collection part) and end-user code must be revisited.

**Instrument 1: Time-Taggina Multiple-Coincidence Detector**

Done